Nuclear Instruments and Methods in Physics Research B63 (1992) 503–510
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Nuclear Instruments & Methods in Physics Research
Section B

Author index

Aboubacar, A., M. Dupont, A. El Manouni, M. Querrou, L.P. Says, N. Fabre and F. Rossel, High field assisted photoemission currents from silicon photocathodes B63 (1992) 489
Achtziger, N., see Forkel, D. B63 (1992) 217
Ackermann, H., see Seelinger, W. B63 (1992) 173
Ahmad, A.A.Z., see Ahmed, F.U. B63 (1992) 333
Ahmed, F.U., M.H. Ahsan, A.A. Khan, I. Kamal, M.A. Awal and A.A.Z. Ahmad, Studies of the behavior of a reactor neutron beam at the sample position of a diffractometer using silicon monochromators B63 (1992) 333
Ahsan, M.H., see Ahmed, F.U. B63 (1992) 333
Al-Bayati, A.H., K.G. Orrman-Rossiter, D.G. Armour, J.A. Van den Berg and S.E. Donnelly, Ion beam deposition and in-situ ion beam analysis B63 (1992) 109
Al Neami, A., A. Kadom Al Neami, M. Bordas, M. Hage-Ali, J. Larcher, P. Siffert and C. Heitz, Ar ion induced X-ray emission for the analysis of light elements in CdTe B63 (1992) 71
Allais, G., see Levalois, M. B63 (1992) 25
Amemiya, H., see Höthker, K. B63 (1992) 484
Ammerlaan, C.A.J., S.J.C.H.M. van Gisbergen, N.T. Son and T. Gregorkiewicz, Nuclear interactions of defects in semiconductors – magnetic resonance measurements B63 (1992) 154
Amsel, G., F. Pászti, E. Szilágyi and J. Gyulai, p, d and α particle discrimination in NRA: thin, adjustable sensitive zone semiconductor detectors revisited B63 (1992) 421
Anagnostopoulos, D., see Ludziejewski, T. B63 (1992) 494
Angius, S.P., R. Elmér, B. Jakobsson, L. Karlsson and K. Söderström, A CCD-based system for analysis of nuclear collisions in photographic emulsion B63 (1992) 359
Armour, D.G., see Al-Bayati, A.H. B63 (1992) 109
Ascheron, C., D. Lehmann, C. Neelmeijer, A. Schindler and F. Bigl, Hydrogen depth profiling in bevelled proton-implanted semiconductors by ^{4}He ERDA and ^{19}F NRA B63 (1992) 412
Assmann, W., see Grötzschel, R. B63 (1992) 77
Austin, J.C., see Hughes, W.C. B63 (1992) 244
Awal, M.A., see Ahmed, F.U. B63 (1992) 333

Baba, Y., H. Yamamoto and T.A. Sasaki, Trapping of low-energy xenon ions in surfaces of transition metals . B63 (1992) 391
Bachmann, T., W. Wesch, K. Gärtner and E. Wendler, Differences in the damage production of proton implanted GaAs, Ge and Si investigated by temperature dependent dechanneling B63 (1992) 64
Backe, H., see Picard, A. B63 (1992) 345
Barrett, J.H., see Comedi, D. B63 (1992) 451
Barth, H., see Picard, A. B63 (1992) 345
Baurichter, A., see Forkel, D. B63 (1992) 217
Behrisch, R., see Grötzschel, R. B63 (1992) 77
Belitz, H.J., see Höthker, K. B63 (1992) 484
Bemelmans, H., G. Borghs and G. Langouche, Mössbauer spectroscopy investigation of the DX-center in Te-implanted $Al_xGa_{1-x}As$ B63 (1992) 151
Bender, H., see Wuyts, K. B63 (1992) 141
Berger, M.G., see Wuyts, K. B63 (1992) 141
Bernaola, O.A., see Mazzei, R. B63 (1992) 309
Berning, P.R. and A. Niiler, Methods of adapting ion beam analysis techniques for use on curved surfaces ... B63 (1992) 434
Bieger, W., see Höthker, K. B63 (1992) 484
Bigl, F., see Ascheron, C. B63 (1992) 412
Blunier, S., V. Meyer, R.E. Pixley, H. Stüssi, S. Teodoropol and H. Zogg, Precision measurement of axial channel angles B63 (1992) 56
Bogdanski, P., see Levalois, M. B63 (1992) 14
Böhringer, K., see Wilbertz, Ch. B63 (1992) 120
Bonn, J., see Picard, A. B63 (1992) 345
Borchert, G., see Ludziejewski, T. B63 (1992) 494
Bordas, M., see Al Neami, A. B63 (1992) 71

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Borghs, G., see Wuyts, K. B63 (1992) 141
Borghs, G., see Bemelmans, H. B63 (1992) 151
Bortolotti, A., J.S. Brzosko, I. Ingrosso, F. Mezzetti, V. Nardi, C. Powell and B.V. Robouch, Inspection of extended objects with fast neutrons: numerical tests B63 (1992) 473
Boudart, B., B. Marí, B. Prévot and C. Schwab, Efficiency of neutron transmutation doping of InP investigated by optical and electrical methods B63 (1992) 101
Bouffard, S., see Rzepka, E. B63 (1992) 270
Brüssler, M., see Dzionk, Chr. B63 (1992) 231
Brzosko, J.S., see Bortolotti, A. B63 (1992) 473
Budnar, M., A. Mühleisen, M. Hribar, H. Jaržekovič, M. Ravnikar, Ž. Šmit and M. Žitnik, K–MM radiative Auger effect in solid Ca, Ti and Cr targets after ionization with 0.7–1.5 MeV protons B63 (1992) 377
Buschhorn, G., see Rzepka, M. B63 (1992) 273
Butz, T., see Unterricker, S. B63 (1992) 236

Calas, J., R. El Ghrandi, G. Galibert and A. Traverse, Photodissolution profile of silver in amorphous chalcogenide $GeSe_x$ thin films B63 (1992) 462
Carin, R., R. Madelon, D. Julienne, F. Cruege and A. Hairie, An investigation by resistance and photoluminescence measurements of high-energy heavy-ion irradiated GaAs B63 (1992) 21
Carlen, M., see Ludziejewski, T. B63 (1992) 494
Chesnokov, Yu.A., V.V. Dudenko, N.A. Galyaev, V.N. Greth, L.A. Kim, V.I. Kotov, A.K. Pudovkin, V.I. Terekhov, S.V. Tsarik and V.N. Zapol'sky, High energy particle beam diagnostics using bent single crystals B63 (1992) 366
Ciocci, F., G. Dattoli, L. Giannessi, C. Mari and A. Torre, Optical properties of helical undulators B63 (1992) 319
Ciocci, F., G. Dattoli, C. Mari and A. Torre, The solenoid as an emittance-flipper device B63 (1992) 326
Comedi, D., R. Kalish and J.H. Barrett, A method for the determination of atomic displacements in compound crystals by means of RBS–PIXE–channeling experiments B63 (1992) 451
Corbel, C., Positron annihilation and charge state of the vacancies in as-grown and electron irradiated GaAs . B63 (1992) 166
Correia, J.G., A.A. Melo, M.F. da Silva, J.C. Soares, H. Haas, M.D. Serrano, E. Dieguez and ISOLDE Collaboration, Hyperfine interactions and Rutherford backscattering studies of Cd and Hg in CdTe single crystals and thin films B63 (1992) 248
Cruege, F., see Carin, R. B63 (1992) 21

Da Silva, M.F., see Correia, J.G. B63 (1992) 248
Da Silva, M.F., see Da Silva, R.C. B63 (1992) 283
Da Silva, R.C., M.F. Da Silva, I. Khubeis, O. Meyer, A.A. Melo and J.C. Soares, Lattice location and diffusion of W implanted in Mg and Al single crystals B63 (1992) 283
Dattoli, G., see Ciocci, F. B63 (1992) 319
Dattoli, G., see Ciocci, F. B63 (1992) 326
Degen, B., see Picard, A. B63 (1992) 345
Deicher, M., PAC studies on the formation and stability of acceptor–defect complexes in semiconductors ... B63 (1992) 189
Deicher, M., see Keller, R. B63 (1992) 202
Deicher, M., see Skudlik, H. B63 (1992) 205
Deicher, M., see Forkel, D. B63 (1992) 217
Deubler, S., see Forkel, D. B63 (1992) 217
Deubler, S., J. Meier, R. Schütz and W. Witthuhn, PAC studies on impurities in ZnO B63 (1992) 223
Diedrich, E., see Rzepka, M. B63 (1992) 273
Dieguez, E., see Correia, J.G. B63 (1992) 248
Diehl, E., see Seelinger, W. B63 (1992) 173
Döbeli, M., U.S. Fischer, M. Suter and W. Wölfli, Application of ^{16}O RBS to heavy compound materials B63 (1992) 68
Dohlus, P. and W. Witthuhn, Quench-induced defects in silicon B63 (1992) 198
Doke, T., N. Ishida and M. Kase, Fano factors in rare gases and their mixtures B63 (1992) 373
Donnelly, S.E., see Al-Bayati, A.H. B63 (1992) 109
Dousse, J-Cl., see Ludziejewski, T. B63 (1992) 494
Doyama, M., Y. Suzuki and M. Shimotomai, Positron annihilation in silicon single crystals B63 (1992) 163
Drentje, A.G., see Ludziejewski, T. B63 (1992) 494
Drigo, A.V., M. Mazzer and F. Romanato, Ion beam analysis of mismatched epitaxial heterostructures B63 (1992) 30
Drigo, A.V., see Romanato, F. B63 (1992) 36
Drigo, A.V., see Leo, G. B63 (1992) 41
Dudenko, V.V., see Chesnokov, Yu.A. B63 (1992) 366
Dupont, M., see Aboubacar, A. B63 (1992) 489
Dzionk, Chr., M. Brüssler and H. Metzner, Development of $CuInS_2$ solar cell material by PAC: bulk phases, thin films, and nuclear reaction doping B63 (1992) 231

Edling, Th., see Picard, A. B63 (1992) 345
Eftekhari, A., see Singh, J.J. B63 (1992) 477
El Ghrandi, R., see Calas, J. B63 (1992) 462
El Manouni, A., see Aboubacar, A. B63 (1992) 489
Elmér, R., see Angius, S.P. B63 (1992) 359
Ergezinger, K.-H., see Seelinger, W. B63 (1992) 173
Eschle, P., see Simmler, H. B63 (1992) 125

Fabre, N., see Aboubacar, A. B63 (1992) 489
Fernández-Varea, J.M., see Salvat, F. B63 (1992) 255
Fischer, B., see Seelinger, W. B63 (1992) 173
Fischer, U.S., see Döbeli, M. B63 (1992) 68
Forkel, D., N. Achtziger, A. Baurichter, M. Deicher, S. Deubler, M. Puschmann, H. Wolf, W. Witthuhn and ISOLDE Collaboration, Acceptor–donor pairs in germanium B63 (1992) 217
Frank, H.-P., see Seelinger, W. B63 (1992) 173
Freitag, K., see Schaefer, Th. B63 (1992) 227
Fujimoto, Y., see Mori, Y. B63 (1992) 395
Fujita, H., see Mori, H. B63 (1992) 291

Galibert, G., see Calas, J. B63 (1992) 462
Galyaev, N.A., see Chesnokov, Yu.A. B63 (1992) 366
Gärtner, K., see Wesch, W. B63 (1992) 52
Gärtner, K., see Götz, G. B63 (1992) 59
Gärtner, K., see Bachmann, T. B63 (1992) 64
Giannessi, L., see Ciocci, F. B63 (1992) 319
Girard, J.P., see Levalois, M. B63 (1992) 25
Golanski, A. and C.W. White, Radiation induced effects in ion beam synthesis of erbium silicide B63 (1992) 384
Götz, G., see Wendler, E. B63 (1992) 47
Götz, G., K. Gärtner and W. Wesch, Investigation of defects by RBS–channeling methods B63 (1992) 59
Gregorkiewicz, T., see Ammerlaan, C.A.J. B63 (1992) 154
Greth, V.N., see Chesnokov, Yu.A. B63 (1992) 366
Grötzschel, R., E. Hentschel, R. Klabes, U. Kreissig, C. Neelmeijer, W. Assmann and R. Behrisch, Elemental analysis of thin layers by elastic heavy ion scattering B63 (1992) 77
Gumlich, H.-E., see Waldmann, H. B63 (1992) 221
Gwilliam, R., B.J. Sealy and R. Vianden, The electrical and radioactive assessment of the transmutation doping of GaAs following implantation by ^{111}In B63 (1992) 106
Gyulai, J., see Amsel, G. B63 (1992) 421

Haas, H., see Correia, J.G. B63 (1992) 248
Hage-Ali, M., see Al Neami, A. B63 (1992) 71
Haid, R., see Picard, A. B63 (1992) 345
Hairie, A., see Carin, R. B63 (1992) 21
Hairie, A., see Levalois, M. B63 (1992) 25
Heitz, C., see Al Neami, A. B63 (1992) 71
Hellborg, R., see Jönsson, G. B63 (1992) 399
Hentschel, E., see Grötzschel, R. B63 (1992) 77
Hermanni, A., see Picard, A. B63 (1992) 345
Hoffmann, H., see Wahl, U. B63 (1992) 91
Hoffmann, H., see Waldmann, H. B63 (1992) 221
Hofsäss, H., S. Winter, S.G. Jahn, U. Wahl, E. Recknagel and ISOLDE Collaboration, Emission channeling studies in semiconductors B63 (1992) 83
Hofsäss, H., see Wahl, U. B63 (1992) 91
Hogmark, S., see Whitlow, H.J. B63 (1992) 445
Holzschuh, E., see Petersen, J.W. B63 (1992) 179
Hoszowska, J., see Ludziejewski, T. B63 (1992) 494
Höthker, K., H. Amemiya, H.J. Belitz, W. Bieger, H. Oyama, Y. Shigueoka and K. Yano, Temperature and density measurements in the RIKEN electron cyclotron discharge ECR-3 ..... B63 (1992) 484
Hourdequin, E., see Rzepka, E. B63 (1992) 270
Hribar, M., see Budnar, M. B63 (1992) 377
Hughes, W.C., M.L. Swanson and J.C. Austin, Perturbed angular correlation observation of vacancy–indium atom defect complexes in (Hg, Cd)Te B63 (1992) 244
Hüttner, D., see Wilbertz, Ch. B63 (1992) 120

Ingemarsson, P.A., see Whitlow, H.J. ... B63 (1992) 445
Ingrosso, I., see Bortolotti, A. ... B63 (1992) 473
Ishida, N., see Doke, T. ... B63 (1992) 373
ISOLDE Collaboration, see Hofsäss, H. ... B63 (1992) 83
ISOLDE Collaboration, see Wahl, U. ... B63 (1992) 91
ISOLDE Collaboration, see Petersen, J.W. ... B63 (1992) 179
ISOLDE Collaboration, see Petersen, J.W. ... B63 (1992) 186
ISOLDE Collaboration, see Forkel, D. ... B63 (1992) 217
ISOLDE Collaboration, see Correia, J.G. ... B63 (1992) 248
Ittermann, B., see Seelinger, W. ... B63 (1992) 173

Jahn, S.G., see Hofsäss, H. ... B63 (1992) 83
Jahn, S.G., see Wahl, U. ... B63 (1992) 91
Jakobsson, B., see Angius, S.P. ... B63 (1992) 359
Jankovski, H., see Korneev, D.A. ... B63 (1992) 328
Janžekovič, H., see Budnar, M. ... B63 (1992) 377
Johansson, E., see Whitlow, H.J. ... B63 (1992) 445
Jönsson, G. and R. Hellborg, The exposure of plastic films and their response to 1.3–5.5 MeV helium ions ... B63 (1992) 399
Jousten, K., see Wilbertz, Ch. ... B63 (1992) 120
Julienne, D., see Carin, R. ... B63 (1992) 21
Jumas, J.C., see Wuyts, K. ... B63 (1992) 141

Kadom Al Neami, A., see Al Neami, A. ... B63 (1992) 71
Kalbitzer, S., Ion beams in semiconductor physics and technology ... B63 (1992) 1
Kalbitzer, S., see Wilbertz, Ch. ... B63 (1992) 120
Kalish, R., see Comedi, D. ... B63 (1992) 451
Kamal, I., see Ahmed, F.U. ... B63 (1992) 333
Karlsson, L., see Angius, S.P. ... B63 (1992) 359
Kase, M., see Doke, T. ... B63 (1992) 373
Keller, H., see Simmler, H. ... B63 (1992) 125
Keller, R., M. Deicher, R. Magerle, W. Pfeiffer, H. Skudlik and Th. Wichert, Dynamic behaviour of Cd–Cu pairs in Si observed by PAC ... B63 (1992) 202
Keller, R., see Skudlik, H. ... B63 (1992) 205
Khan, A.A., see Ahmed, F.U. ... B63 (1992) 333
Khubeis, I., see Da Silva, R.C. ... B63 (1992) 283
Kim, L.A., see Chesnokov, Yu.A. ... B63 (1992) 366
Klabes, R., see Grötzschel, R. ... B63 (1992) 77
Knauf, H., see Schaefer, Th. ... B63 (1992) 227
Korneev, D.A., V.V. Pasyuk, A.V. Petrenko and H. Jankovski, Absorbing sublayers and their influence on the polarizing efficiency of magnetic neutron mirrors ... B63 (1992) 328
Kotov, V.I., see Chesnokov, Yu.A. ... B63 (1992) 366
Koyama, H., see Mori, H. ... B63 (1992) 291
Kreissig, U., see Grötzschel, R. ... B63 (1992) 77
Krings, Th., see Wolf, H. ... B63 (1992) 240
Kündig, W., see Simmler, H. ... B63 (1992) 125
Kundig, W., see Petersen, J.W. ... B63 (1992) 179

Langouche, G., see Vantomme, A. ... B63 (1992) 130
Langouche, G., see Wuyts, K. ... B63 (1992) 141
Langouche, G., see Bemelmans, H. ... B63 (1992) 151
Larcher, J., see Al Neami, A. ... B63 (1992) 71
Lefrant, S., see Rzepka, E. ... B63 (1992) 270
Lehmann, D., see Ascheron, C. ... B63 (1992) 412
Leiderer, P., see Picard, A. ... B63 (1992) 345
Leo, G., A. Traverse, M.O. Ruault and A.V. Drigo, Ion channeling study of P implantation damage in CdTe ... B63 (1992) 41
Levalois, M., P. Bogdanski and M. Toulemonde, Induced damage by high energy heavy ion irradiation at the GANIL accelerator in semiconductor materials ... B63 (1992) 14
Levalois, M., J.P. Girard, G. Allais, A. Hairie, M.N. Metzner and E. Paumier, High energy ion irradiation of germanium ... B63 (1992) 25
Liang, Z.N. and L. Niesen, Donor–hydrogen complexes in silicon studied by Mössbauer spectroscopy ... B63 (1992) 147
Loeken, Th., see Picard, A. ... B63 (1992) 345

Lohmann, E., see Schaefer, Th. B63 (1992) 227
Ludziejewski, T., J. Hoszowska, P. Rymuza, Z. Sujkowski, D. Anagnostopoulos, G. Borchert, M. Carlen, J-Cl. Dousse, Ch. Rhême and A.G. Drentje, In-beam bent-crystal spectrometer for studies of multiple inner shell ionization (*Letter to the Editor*) B63 (1992) 494
Lüth, H., see Wuyts, K. B63 (1992) 141

Madelon, R., see Carin, R. B63 (1992) 21
Magerle, R., see Keller, R. B63 (1992) 202
Magerle, R., see Skudlik, H. B63 (1992) 205
Mahnke, H.-E., see Waldmann, H. B63 (1992) 221
Mai, F., see Seelinger, W. B63 (1992) 173
Maisch, Th., see Wilbertz, Ch. B63 (1992) 120
Marí, B., see Boudart, B. B63 (1992) 101
Mari, C., see Ciocci, F. B63 (1992) 319
Mari, C., see Ciocci, F. B63 (1992) 326
Mazzei, R. and O.A. Bernaola, Track experimental data related to post-irradiation dynamic processes B63 (1992) 309
Mazzer, M., see Drigo, A.V. B63 (1992) 30
Mazzer, M., see Romanato, F. B63 (1992) 36
Mdebuka, A.M., Thermoluminescent properties and defect stability in silver doped crystals B63 (1992) 407
Meier, J., see Deubler, S. B63 (1992) 223
Melo, A.A., see Correia, J.G. B63 (1992) 248
Melo, A.A., see Da Silva, R.C. B63 (1992) 283
Metzner, H., see Dzionk, Chr. B63 (1992) 231
Metzner, M.N., see Levalois, M. B63 (1992) 25
Meyer, O., see Da Silva, R.C. B63 (1992) 283
Meyer, V., see Blunier, S. B63 (1992) 56
Mezzetti, F., see Bortolotti, A. B63 (1992) 473
Miyajima, M., S. Sasaki and E. Shibamura, Absolute number of photons produced by alpha-particles in liquid and gaseous xenon B63 (1992) 297
Molz, A., see Picard, A. B63 (1992) 345
Moore, R.B., see Picard, A. B63 (1992) 345
Mori, H., H. Yasuda, H. Koyama, N. Sumida and H. Fujita, Electron-irradiation-induced gold atom implantation into a silicon substrate and AES analysis of the gold-implanted silicon B63 (1992) 291
Mori, Y., Y. Fujimoto and F. Okuyama, Structural details of copper seed cones revealed by high-resolution electron microscopy B63 (1992) 395
Mühleisen, A., see Budnar, M. B63 (1992) 377
Münder, H., see Wuyts, K. B63 (1992) 141

Nardi, V., see Bortolotti, A. B63 (1992) 473
Neelmeijer, C., see Grötzschel, R. B63 (1992) 77
Neelmeijer, C., see Ascheron, C. B63 (1992) 412
Nielsen, J., see Petersen, J.W. B63 (1992) 186
Niesen, L., see Spanninga, W.G. B63 (1992) 138
Niesen, L., see Liang, Z.N. B63 (1992) 147
Niiler, A., see Berning, P.R. B63 (1992) 434

Odermatt, W., see Simmler, H. B63 (1992) 125
Okuyama, F., see Mori, Y. B63 (1992) 395
Orrman-Rossiter, K.G., see Al-Bayati, A.H. B63 (1992) 109
Osipowicz, A., see Picard, A. B63 (1992) 345
Otten, E.W., see Picard, A. B63 (1992) 345
Oyama, H., see Höthker, K. B63 (1992) 484

Pasyuk, V.V., see Korneev, D.A. B63 (1992) 328
Pászti, F., see Amsel, G. B63 (1992) 421
Patterson, B.D., see Simmler, H. B63 (1992) 125
Pattyn, H., see Wuyts, K. B63 (1992) 141
Paumier, E., see Levalois, M. B63 (1992) 25
Petersen, J.W., G. Weyer, A. Svane, E. Holzschuh, W. Kundig and ISOLDE Collaboration, High resolution conversion electron spectroscopy of impurities in semiconductors B63 (1992) 179
Petersen, J.W., J. Nielsen and ISOLDE Collaboration, Identification of band gap states by deep level transient spectroscopy on radioactive probes B63 (1992) 186

Petrenko, A.V., see Korneev, D.A. B63 (1992) 328
Pfeiffer, W., see Keller, R. B63 (1992) 202
Pfeiffer, W., see Skudlik, H. B63 (1992) 205
Picard, A., H. Backe, H. Barth, J. Bonn, B. Degen, Th. Edling, R. Haid, A. Hermanni, P. Leiderer, Th. Loeken, A. Molz, R.B. Moore, A. Osipowicz, E.W. Otten, M. Przyrembel, M. Schrader, M. Steininger and Ch. Weinheimer, A solenoid retarding spectrometer with high resolution and transmission for keV electrons B63 (1992) 345
Pixley, R.E., see Blunier, S. B63 (1992) 56
Powell, C., see Bortolotti, A. B63 (1992) 473
Prévot, B., see Boudart, B. B63 (1992) 101
Pross, P., see Skudlik, H. B63 (1992) 205
Przyrembel, M., see Picard, A. B63 (1992) 345
Pudovkin, A.K., see Chesnokov, Yu.A. B63 (1992) 366
Puschmann, M., see Forkel, D. B63 (1992) 217

Querrou, M., see Aboubacar, A. B63 (1992) 489

Ramstein, B., see Rzepka, E. B63 (1992) 270
Ravnikar, M., see Budnar, M. B63 (1992) 377
Recknagel, E., see Hofsäss, H. B63 (1992) 83
Recknagel, E., see Wahl, U. B63 (1992) 91
Rhême, Ch., see Ludziejewski, T. B63 (1992) 494
Robouch, B.V., see Bortolotti, A. B63 (1992) 473
Romanato, F., see Drigo, A.V. B63 (1992) 30
Romanato, F., M. Mazzer and A.V. Drigo, Dechanneling cross section for misfit dislocations B63 (1992) 36
Rossel, F., see Aboubacar, A. B63 (1992) 489
Ruault, M.O., see Leo, G. B63 (1992) 41
Rymuza, P., see Ludziejewski, T. B63 (1992) 494
Rzepka, E., J. Wery, S. Lefrant, B. Ramstein, R. Tamisier, E. Hourdequin and S. Bouffard, Creation of molecular defects in alkali iodide crystals by irradiation with fast heavy ions B63 (1992) 270
Rzepka, M., E. Diedrich and G. Buschhorn, Monte Carlo study of shower formation from high energy electrons and photons in aligned crystals B63 (1992) 273

Saibene, S., see Unterricker, S. B63 (1992) 236
Salvat, F. and J.M. Fernández-Varea, Semiempirical cross sections for the simulation of the energy loss of electrons and positrons in matter B63 (1992) 255
Sasaki, S., see Miyajima, M. B63 (1992) 297
Sasaki, T.A., see Baba, Y. B63 (1992) 391
Savić, I.M., see Simmler, H. B63 (1992) 125
Says, L.P., see Aboubacar, A. B63 (1992) 489
Schaefer, Th., H. Knauf, E. Lohmann, R. Vianden and K. Freitag, PAC investigations of the shallow donor environment in GaAs B63 (1992) 227
Schindler, A., see Ascheron, C. B63 (1992) 412
Schneider, J.W., see Simmler, H. B63 (1992) 125
Schrader, M., see Picard, A. B63 (1992) 345
Schütz, R., see Deubler, S. B63 (1992) 223
Schwab, C., see Boudart, B. B63 (1992) 101
Sealy, B.J., see Gwilliam, R. B63 (1992) 106
Seelinger, W., B. Fischer, E. Diehl, K.-H. Ergezinger, H.-P. Frank, B. Ittermann, F. Mai, G. Welker, H. Ackermann and H.-J. Stöckmann, β-NMR study on the lattice locations of boron implanted into silicon .. B63 (1992) 173
Serrano, M.D., see Correia, J.G. B63 (1992) 248
Shibamura, E., see Miyajima, M. B63 (1992) 297
Shigueoka, Y., see Höthker, K. B63 (1992) 484
Shimotomai, M., see Doyama, M. B63 (1992) 163
Siffert, P., see Al Neami, A. B63 (1992) 71
Silverans, R E., see Wuyts, K. B63 (1992) 141
Simmler, H., P. Eschle, H. Keller, W. Kündig, W. Odermatt, B.D. Patterson, I.M. Savić, J.W. Schneider, B. Stäuble-Pümpin, U. Straumann and P. Truöl, Muon-decay positron channeling in semiconductors B63 (1992) 125
Singh, J.J. and A. Eftekhari, Free volume model for molecular weights of polymers B63 (1992) 477
Skudlik, H., see Keller, R. B63 (1992) 202
Skudlik, H., M. Deicher, R. Keller, R. Magerle, W. Pfeiffer, P. Pross and Th. Wichert, Hydrogen passivation of acceptors in silicon: a combined PAC and resistivity study B63 (1992) 205

Šmit, Ž., see Budnar, M. B63 (1992) 377
Smulders, P.J.M., see Spanninga, W.G. B63 (1992) 138
Soares, J.C., see Correia, J.G. B63 (1992) 248
Soares, J.C., see Da Silva, R.C. B63 (1992) 283
Söderström, K., see Angius, S.P. B63 (1992) 359
Son, N.T., see Ammerlaan, C.A.J. B63 (1992) 154
Spanninga, W.G., P.J.M. Smulders and L. Niesen, Mössbauer and channeling measurements on buried layers of $CoSi_2$ in Si B63 (1992) 138
Spellmeyer, B., see Waldmann, H. B63 (1992) 221
Stäuble-Pümpin, B., see Simmler, H. B63 (1992) 125
Steininger, M., see Picard, A. B63 (1992) 345
Stöckmann, H.-J., see Seelinger, W. B63 (1992) 173
Straumann, U., see Simmler, H. B63 (1992) 125
Stüssi, H., see Blunier, S. B63 (1992) 56
Sujkowski, Z., see Ludziejewski, T. B63 (1992) 494
Sulzer, G., see Waldmann, H. B63 (1992) 221
Sumida, N., see Mori, H. B63 (1992) 291
Suter, M., see Döbeli, M. B63 (1992) 68
Suzuki, Y., see Doyama, M. B63 (1992) 163
Svane, A., see Petersen, J.W. B63 (1992) 179
Swanson, M.L., see Hughes, W.C. B63 (1992) 244
Szilágyi, E., see Amsel, G. B63 (1992) 421

Tamisier, R., see Rzepka, E. B63 (1992) 270
Teodoropol, S., see Blunier, S. B63 (1992) 56
Terekhov, V.I., see Chesnokov, Yu.A. B63 (1992) 366
Torre, A., see Ciocci, F. B63 (1992) 319
Torre, A., see Ciocci, F. B63 (1992) 326
Toulemonde, M., see Levalois, M. B63 (1992) 14
Traverse, A., see Leo, G. B63 (1992) 41
Traverse, A., see Calas, J. B63 (1992) 462
Truöl, P., see Simmler, H. B63 (1992) 125
Tsarik, S.V., see Chesnokov, Yu.A. B63 (1992) 366

Unterricker, S., T. Butz and S. Saibene, Annealing of lattice defects in chalcopyrite semiconductors – TDPAC investigations B63 (1992) 236

Van den Berg, J.A., see Al-Bayati, A.H. B63 (1992) 109
Van Gisbergen, S.J.C.H.M., see Ammerlaan, C.A.J. B63 (1992) 154
Van Hove, M., see Wuyts, K. B63 (1992) 141
Van Rossum, M., see Wuyts, K. B63 (1992) 141
Vanderstraeten, H., see Wuyts, K. B63 (1992) 141
Vantomme, A., M.F. Wu and G. Langouche, Single and double buried epitaxial metallic layers in Si prepared by ion implantation B63 (1992) 130
Vianden, R., see Gwilliam, R. B63 (1992) 106
Vianden, R., see Schaefer, Th. B63 (1992) 227
Von Ammon, W., Neutron transmutation doped silicon – technological and economic aspects B63 (1992) 95

Wahl, U., see Hofsäss, H. B63 (1992) 83
Wahl, U., H. Hofsäss, S.G. Jahn, S. Winter, H. Hoffmann, E. Recknagel and ISOLDE Collaboration, Lattice site changes of ion implanted ^{8}Li in Si studied by alpha emission channeling B63 (1992) 91
Waldmann, H., H.-E. Mahnke, B. Spellmeyer, G. Sulzer, W.-D. Zeitz, H. Hoffmann and H.-E. Gumlich, Magnetic behavior of isolated Fe and Ni ions in semiconducting compounds B63 (1992) 221
Watté, J., see Wuyts, K. B63 (1992) 141
Weinheimer, Ch., see Picard, A. B63 (1992) 345
Welker, G., see Seelinger, W. B63 (1992) 173
Wendler, E., W. Wesch and G. Götz, Investigation of the amorphization process in ion implanted $A_{III}B_{V}$ compounds B63 (1992) 47
Wendler, E., see Wesch, W. B63 (1992) 52
Wendler, E., see Bachmann, T. B63 (1992) 64
Wery, J., see Rzepka, E. B63 (1992) 270

Wesch, W., see Wendler, E. B63 (1992) 47
Wesch, W., E. Wendler and K. Gärtner, Nucleation of point defects in low-fluence ion-implanted GaAs and GaP B63 (1992) 52
Wesch, W., see Götz, G. B63 (1992) 59
Wesch, W., see Bachmann, T. B63 (1992) 64
Weyer, G., see Petersen, J.W. B63 (1992) 179
White, C.W., see Golanski, A. B63 (1992) 384
Whitlow, H.J., E. Johansson, P.A. Ingemarsson and S. Hogmark, Recoil spectrometry of oil additive associated compositional changes in sliding metal surfaces B63 (1992) 445
Wichert, Th., see Keller, R. B63 (1992) 202
Wichert, Th., see Skudlik, H. B63 (1992) 205
Wichert, Th., see Wolf, H. B63 (1992) 240
Wilbertz, Ch., Th. Maisch, D. Hüttner, K. Böhringer, K. Jousten and S. Kalbitzer, A focused gas–ion beam system for submicron application B63 (1992) 120
Winter, S., see Hofsäss, H. B63 (1992) 83
Winter, S., see Wahl, U. B63 (1992) 91
Witthuhn, W., see Dohlus, P. B63 (1992) 198
Witthuhn, W., Dynamics and electronic transitions at impurity complexes in semiconductors B63 (1992) 209
Witthuhn, W., see Forkel, D. B63 (1992) 217
Witthuhn, W., see Deubler, S. B63 (1992) 223
Wolf, H., see Forkel, D. B63 (1992) 217
Wolf, H., Th. Krings and Th. Wichert, Generation of intrinsic defects in CdSi:In by doping with Li atoms ... B63 (1992) 240
Wölfli, W., see Döbeli, M. B63 (1992) 68
Wu, M.F., see Vantomme, A. B63 (1992) 130
Wuyts, K., J. Watté, H. Vanderstraeten, H. Pattyn, G. Langouche, R.E. Silverans, H. Münder, M.G. Berger, H. Lüth, G. Zégbé, J.C. Jumas, M. van Hove, H. Bender, G. Borghs and M. van Rossum, A ^{129}I Mössbauer investigation of the ohmic contact formation mechanism in the Au/Te/Au/n-GaAs system, questioned and confirmed by X-ray analysis and Raman spectroscopy B63 (1992) 141

Yamamoto, H., see Baba, Y. B63 (1992) 391
Yano, K., see Höthker, K. B63 (1992) 484
Yasuda, H., see Mori, H. B63 (1992) 291

Zapol'sky, V.N., see Chesnokov, Yu.A. B63 (1992) 366
Zégbé, G., see Wuyts, K. B63 (1992) 141
Zeitz, W.-D., see Waldmann, H. B63 (1992) 221
Žitnik, M., see Budnar, M. B63 (1992) 377
Zogg, H., see Blunier, S. B63 (1992) 56

Nuclear Instruments and Methods in Physics Research B63 (1992) 511–513
North-Holland

Nuclear Instruments & Methods in Physics Research
Section B

Subject index

Basic data for materials modification and analysis

Semiempirical cross sections for the simulation of the energy loss of electrons and positrons in matter, Salvat, F. and J.M. Fernández-Varea B63 (1991) 255
Fano factors in rare gases and their mixtures, Doke, T., N. Ishida and M. Kase B63 (1991) 373
K–MM radiative Auger effect in solid Ca, Ti and Cr targets after ionization with 0.7–1.5 MeV protons, Budnar, M., A. Mühleisen, M. Hribar, H. Janžekovič, M. Ravnikar, Ž. Šmit and M. Žitnik B63 (1991) 377

Atomic collisions in solids

Creation of molecular defects in alkali iodide crystals by irradiation with fast heavy ions, Rzepka, E., J. Wery, S. Lefrant, B. Ramstein, R. Tamisier, E. Hourdequin and S. Bouffard B63 (1991) 270
Monte Carlo study of shower formation from high energy electrons and photons in aligned crystals, Rzepka, M., E. Diedrich and G. Buschhorn B63 (1991) 273

Ion beam modification of materials

Lattice location and diffusion of W implanted in Mg and Al single crystals, Da Silva, R.C., M.F. Da Silva, I. Khubeis, O. Meyer, A.A. Melo and J.C. Soares B63 (1991) 283
Radiation induced effects in ion beam synthesis of erbium silicide, Golanski, A. and C.W. White B63 (1991) 384

Effects of radiation

Electron-irradiation-induced gold atom implantation into a silicon substrate and AES analysis of the gold-implanted silicon, Mori, H., H. Yasuda, H. Koyama, N. Sumida and H. Fujita B63 (1991) 291
Absolute number of photons produced by alpha-particles in liquid and gaseous xenon, Miyajima, M., S. Sasaki and E. Shibamura B63 (1991) 297
Track experimental data related to post-irradiation dynamic processes, Mazzei, R. and O.A. Bernaola B63 (1991) 309
Trapping of low-energy xenon ions in surfaces of transition metals, Baba, Y., H. Yamamoto and T.A. Sasaki .. B63 (1991) 391
Structural details of copper seed cones revealed by high-resolution electron microscopy, Mori, Y., Y. Fujimoto and F. Okuyama B63 (1991) 395
The exposure of plastic films and their response to 1.3–5.5 MeV helium ions, Jönsson, G. and R. Hellborg ... B63 (1991) 399
Thermoluminescent properties and defect stability in silver doped crystals, Mdebuka, A.M. B63 (1991) 407

Analysis of materials

Proceedings of E-MRS Spring Meeting, Symposium F: Nuclear methods in semiconductor physics (Strasbourg, France, May 28–30, 1991)

Ion beams in semiconductor physics and technology, Kalbitzer, S. B63 (1991) 1
Induced damage by high energy heavy ion irradiation at the GANIL accelerator in semiconductor materials, Levalois, M., P. Bogdanski and M. Toulemonde B63 (1991) 14
An investigation by resistance and photoluminescence measurements of high-energy heavy-ion irradiated GaAs, Carin, R., R. Madelon, D. Julienne, F. Cruege and A. Hairie B63 (1991) 21
High energy ion irradiation of germanium, Levalois, M., J.P. Girard, G. Allais, A. Hairie, M.N. Metzner and E. Paumier B63 (1991) 25
Ion beam analysis of mismatched epitaxial heterostructures, Drigo, A.V., M. Mazzer and F. Romanato B63 (1991) 30
Dechanneling cross section for misfit dislocations, Romanato, F., M. Mazzer and A.V. Drigo B63 (1991) 36
Ion channeling study of P implantation damage in CdTe, Leo, G., A. Traverse, M.O. Ruault and A.V. Drigo . B63 (1991) 41

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Investigation of the amorphization process in ion implanted $A_{III}B_V$ compounds, Wendler, E., W. Wesch and G. Götz B63 (1991) 47
Nucleation of point defects in low-fluence ion-implanted GaAs and GaP, Wesch, W., E. Wendler and K. Gärtner B63 (1991) 52
Precision measurement of axial channel angles, Blunier, S., V. Meyer, R.E. Pixley, H. Stüssi, S. Teodoropol and H. Zogg B63 (1991) 56
Investigation of defects by RBS–channeling methods, Götz, G., K. Gärtner and W. Wesch B63 (1991) 59
Differences in the damage production of proton implanted GaAs, Ge and Si investigated by temperature dependent dechanneling, Bachmann, T., W. Wesch, K. Gärtner and E. Wendler B63 (1991) 64
Application of ^{16}O RBS to heavy compound materials, Döbeli, M., U.S. Fischer, M. Suter and W. Wölfli B63 (1991) 68
Ar ion induced X-ray emission for the analysis of light elements in CdTe, Al Neami, A., A. Kadom Al Neami, M. Bordas, M. Hage-Ali, J. Larcher, P. Siffert and C. Heitz B63 (1991) 71
Elemental analysis of thin layers by elastic heavy ion scattering, Grötzschel, R., E. Hentschel, R. Klabes, U. Kreissig, C. Neelmeijer, W. Assmann and R. Behrisch B63 (1991) 77
Emission channeling studies in semiconductors, Hofsäss, H., S. Winter, S.G. Jahn, U. Wahl, E. Recknagel and ISOLDE Collaboration B63 (1991) 83
Lattice site changes of ion implanted ^{8}Li in Si studied by alpha emission channeling, Wahl, U., H. Hofsäss, S.G. Jahn, S. Winter, H. Hoffmann, E. Recknagel and ISOLDE Collaboration B63 (1991) 91
Neutron transmutation doped silicon – technological and economic aspects, Von Ammon, W. B63 (1991) 95
Efficiency of neutron transmutation doping of InP investigated by optical and electrical methods, Boudart, B., B. Marí, B. Prévot and C. Schwab B63 (1991) 101
The electrical and radioactive assessment of the transmutation doping of GaAs following implantation by ^{111}In, Gwilliam, R., B.J. Sealy and R. Vianden B63 (1991) 106
Ion beam deposition and in-situ ion beam analysis, Al-Bayati, A.H., K.G. Orrman-Rossiter, D.G. Armour, J.A. Van den Berg and S.E. Donnelly B63 (1991) 109
A focused gas–ion beam system for submicron application, Wilbertz, Ch., Th. Maisch, D. Hüttner, K. Böhringer, K. Jousten and S. Kalbitzer B63 (1991) 120
Muon-decay positron channeling in semiconductors, Simmler, H., P. Eschle, H. Keller, W. Kündig, W. Odermatt, B.D. Patterson, I.M. Savić, J.W. Schneider, B. Stäuble-Pümpin, U. Straumann and P. Truöl ... B63 (1991) 125
Single and double buried epitaxial metallic layers in Si prepared by ion implantation, Vantomme, A., M.F. Wu and G. Langouche B63 (1991) 130
Mössbauer and channeling measurements on buried layers of $CoSi_2$ in Si, Spanninga, W.G., P.J.M. Smulders and L. Niesen B63 (1991) 138
A ^{129}I Mössbauer investigation of the ohmic contact formation mechanism in the Au/Te/Au/n-GaAs system, questioned and confirmed by X-ray analysis and Raman spectroscopy, Wuyts, K., J. Watté, H. Vanderstraeten, H. Pattyn, G. Langouche, R.E. Silverans, H. Münder, M.G. Berger, H. Lüth, G. Zégbé, J.C. Jumas, M. van Hove, H. Bender, G. Borghs and M. van Rossum B63 (1991) 141
Donor–hydrogen complexes in silicon studied by Mössbauer spectroscopy, Liang, Z.N. and L. Niesen B63 (1991) 147
Mössbauer spectroscopy investigation of the DX-center in Te-implanted $Al_xGa_{1-x}As$, Bemelmans, H., G. Borghs and G. Langouche B63 (1991) 151
Nuclear interactions of defects in semiconductors – magnetic resonance measurements, Ammerlaan, C.A.J., S.J.C.H.M. van Gisbergen, N.T. Son and T. Gregorkiewicz B63 (1991) 154
Positron annihilation in silicon single crystals, Doyama, M., Y. Suzuki and M. Shimotomai B63 (1991) 163
Positron annihilation and charge state of the vacancies in as-grown and electron irradiated GaAs, Corbel, C. . B63 (1991) 166
β-NMR study on the lattice locations of boron implanted into silicon, Seelinger, W., B. Fischer, E. Diehl, K.-H. Ergezinger, H.-P. Frank, B. Ittermann, F. Mai, G. Welker, H. Ackermann and H.-J. Stöckmann B63 (1991) 173
High resolution conversion electron spectroscopy of impurities in semiconductors, Petersen, J.W., G. Weyer, A. Svane, E. Holzschuh, W. Kundig and ISOLDE Collaboration B63 (1991) 179
Identification of band gap states by deep level transient spectroscopy on radioactive probes, Petersen, J.W., J. Nielsen and ISOLDE Collaboration B63 (1991) 186
PAC studies on the formation and stability of acceptor–defect complexes in semiconductors, Deicher, M. B63 (1991) 189
Quench-induced defects in silicon, Dohlus, P. and W. Witthuhn B63 (1991) 198
Dynamic behaviour of Cd–Cu pairs in Si observed by PAC, Keller, R., M. Deicher, R. Magerle, W. Pfeiffer, H. Skudlik and Th. Wichert B63 (1991) 202
Hydrogen passivation of acceptors in silicon: a combined PAC and resistivity study, Skudlik, H., M. Deicher, R. Keller, R. Magerle, W. Pfeiffer, P. Pross and Th. Wichert B63 (1991) 205
Dynamics and electronic transitions at impurity complexes in semiconductors, Witthuhn, W. B63 (1991) 209
Acceptor–donor pairs in germanium, Forkel, D., N. Achtziger, A. Baurichter, M. Deicher, S. Deubler, M. Puschmann, H. Wolf, W. Witthuhn and ISOLDE Collaboration B63 (1991) 217
Magnetic behavior of isolated Fe and Ni ions in semiconducting compounds, Waldmann, H., H.-E. Mahnke, B. Spellmeyer, G. Sulzer, W.-D. Zeitz, H. Hoffmann and H.-E. Gumlich B63 (1991) 221

PAC studies on impurities in ZnO, Deubler, S., J. Meier, R. Schütz and W. Witthuhn B63 (1991) 223
PAC investigations of the shallow donor environment in GaAs, Schaefer, Th., H. Knauf, E. Lohmann, R. Vianden and K. Freitag B63 (1991) 227
Development of $CuInS_2$ solar cell material by PAC: bulk phases, thin films, and nuclear reaction doping, Dzionk, Chr., M. Brüssler and H. Metzner B63 (1991) 231
Annealing of lattice defects in chalcopyrite semiconductors – TDPAC investigations, Unterricker, S., T. Butz and S. Saibene B63 (1991) 236
Generation of intrinsic defects in CdSi:In by doping with Li atoms, Wolf, H., Th. Krings and Th. Wichert B63 (1991) 240
Perturbed angular correlation observation of vacancy–indium atom defect complexes in (Hg, Cd)Te, Hughes, W.C., M.L. Swanson and J.C. Austin B63 (1991) 244
Hyperfine interactions and Rutherford backscattering studies of Cd and Hg in CdTe single crystals and thin films, Correia, J.G., A.A. Melo, M.F. da Silva, J.C. Soares, H. Haas, M.D. Serrano, E. Dieguez and ISOLDE Collaboration B63 (1991) 248

Hydrogen depth profiling in bevelled proton-implanted semiconductors by ^4He ERDA and ^{19}F NRA, Ascheron, C., D. Lehmann, C. Neelmeijer, A. Schindler and F. Bigl B63 (1991) 412
p, d and α particle discrimination in NRA: thin, adjustable sensitive zone semiconductor detectors revisited, Amsel, G., F. Pászti, E. Szilágyi and J. Gyulai B63 (1991) 421
Methods of adapting ion beam analysis techniques for use on curved surfaces, Berning, P.R. and A. Niiler ... B63 (1991) 434
Recoil spectrometry of oil additive associated compositional changes in sliding metal surfaces, Whitlow, H.J., E. Johansson, P.A. Ingemarsson and S. Hogmark B63 (1991) 445
A method for the determination of atomic displacements in compound crystals by means of RBS–PIXE–channeling experiments, Comedi, D., R. Kalish and J.H. Barrett B63 (1991) 451
Photodissolution profile of silver in amorphous chalcogenide $GeSe_x$ thin films, Calas, J., R. El Ghrandi, G. Galibert and A. Traverse B63 (1991) 462
Inspection of extended objects with fast neutrons: numerical tests, Bortolotti, A., J.S. Brzosko, I. Ingrosso, F. Mezzetti, V. Nardi, C. Powell and B.V. Robouch B63 (1991) 473
Free volume model for molecular weights of polymers, Singh, J.J. and A. Eftekhari B63 (1991) 477

Experimental methods and equipment

Optical properties of helical undulators, Ciocci, F., G. Dattoli, L. Giannessi, C. Mari and A. Torre B63 (1991) 319
The solenoid as an emittance-flipper device, Ciocci, F., G. Dattoli, C. Mari and A. Torre B63 (1991) 326
Absorbing sublayers and their influence on the polarizing efficiency of magnetic neutron mirrors, Korneev, D.A., V.V. Pasyuk, A.V. Petrenko and H. Jankovski B63 (1991) 328
Studies of the behavior of a reactor neutron beam at the sample position of a diffractometer using silicon monochromators, Ahmed, F.U., M.H. Ahsan, A.A. Khan, I. Kamal, M.A. Awal and A.A.Z. Ahmad B63 (1991) 333
A solenoid retarding spectrometer with high resolution and transmission for keV electrons, Picard, A., H. Backe, H. Barth, J. Bonn, B. Degen, Th. Edling, R. Haid, A. Hermanni, P. Leiderer, Th. Loeken, A. Molz, R.B. Moore, A. Osipowicz, E.W. Otten, M. Przyrembel, M. Schrader, M. Steininger and Ch. Weinheimer . B63 (1991) 345
A CCD-based system for analysis of nuclear collisions in photographic emulsion, Angius, S.P., R. Elmér, B. Jakobsson, L. Karlsson and K. Söderström B63 (1991) 359
High energy particle beam diagnostics using bent single crystals, Chesnokov, Yu.A., V.V. Dudenko, N.A. Galyaev, V.N. Greth, L.A. Kim, V.I. Kotov, A.K. Pudovkin, V.I. Terekhov, S.V. Tsarik and V.N. Zapol'sky B63 (1991) 366
Temperature and density measurements in the RIKEN electron cyclotron discharge ECR-3, Höthker, K., H. Amemiya, H.J. Belitz, W. Bieger, H. Oyama, Y. Shigueoka and K. Yano B63 (1991) 484
High field assisted photoemission currents from silicon photocathodes, Aboubacar, A., M. Dupont, A. El Manouni, M. Querrou, L.P. Says, N. Fabre and F. Rossel B63 (1991) 489
In-beam bent-crystal spectrometer for studies of multiple inner shell ionization (*Letter to the Editor*), Ludziejewski, T., J. Hoszowska, P. Rymuza, Z. Sujkowski, D. Anagnostopoulos, G. Borchert, M. Carlen, J-Cl. Dousse, Ch. Rhême and A.G. Drentje B63 (1991) 494

Letters to the editor

In-beam bent-crystal spectrometer for studies of multiple inner shell ionization, Ludziejewski, T., J. Hoszowska, P. Rymuza, Z. Sujkowski, D. Anagnostopoulos, G. Borchert, M. Carlen, J-Cl. Dousse, Ch. Rhême and A.G. Drentje B63 (1991) 494